


<b>Search Notes</b>  	<b>Application/Control No.</b>  10763224	<b>Applicant(s)/Patent Under Reexamination</b>  CHO, BYOUNG-WOO
	<b>Examiner</b>  Haney, Richale L	<b>Art Unit</b>  3765

SEARCHED			
Class	Subclass	Date	Examiner
2	181, 195.1	08/03/2006	RLH
above	updated	2/2/2007	RLH
above	updated	9/30/2008	RLQ
2	171, 195.3, 209.12, 195.2, 181.4, 209.3, dig. 11	9/30/2008	RLQ
above	updated	5/7/09	RLQ

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST search printout	08/03/2006update	RLH
See EAST search printout	9/30/2008	RLQ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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